



PATENT  
455610-2590.1

IFW

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant : Martin MILLER et al.  
Serial No. : 10/673,736  
Filed : September 29, 2003  
Title : METHOD OF ANALYZING SERIAL DATA STREAMS  
Art Unit : 2184  
Examiner : To Be Assigned

745 Fifth Avenue  
New York, NY 10151

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on December 3, 2004.

William S. Frommer, Reg. No. 25,506

\_\_\_\_\_  
Name of Applicant, Assignee or Registered Representative



\_\_\_\_\_  
Signature

December 3, 2004

\_\_\_\_\_  
Date of Signature

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir

In compliance with the duty of disclosure set forth in 37 C.F.R. 1.56, Applicants are filing this Supplemental Information Disclosure Statement, the accompanying form PTO-1449 and the documents noted thereon.

So far as Applicants are aware, this Supplemental Information Disclosure Statement is being filed before the mailing date of the first Office Action on the merits.


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The filing of this Information Disclosure Statement is not an admission that the documents identified herein constitute prior art to the present application.

It is believed that no fees are required by the instant submission as it is prior to receipt of the first Office Action in this application. However, if any fees are required, or if any overpayment has been made, please charge Deposit Acct. No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP  
Attorney for Applicants

By:   
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Encs. - PTO Form 1449

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U.S. PATENT DOCUMENTS

| EXAMINER<br>INITIAL |    | DOCUMENT NUMBER | DATE     | NAME            | CLASS | SUBCLASS | FILING DATE<br>IF APPROPRIATE |
|---------------------|----|-----------------|----------|-----------------|-------|----------|-------------------------------|
|                     | AA | 5,654,987       | 08/05/97 | Nakamura        |       |          |                               |
|                     | AB | 5,726,607       | 03/10/98 | Brede et al     |       |          |                               |
|                     | AC | 5,825,825       | 10/20/98 | Altmann et al   |       |          |                               |
|                     | AD | 5,900,755       | 05/04/99 | Toeppen et al   |       |          |                               |
|                     | AE | 6,215,363       | 04/10/01 | Conta et al     |       |          |                               |
|                     | AF | 6,295,327       | 09/25/01 | Takla           |       |          |                               |
|                     | AG | 6,445,230       | 09/03/02 | Rupp et al      |       |          |                               |
|                     | AH | 4,680,778       | 07/14/87 | Krinoch         |       |          |                               |
|                     | AI | 5,943,378       | 08/24/99 | Keba et al      |       |          |                               |
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|                     | AK | 5,914,592       | 06/22/99 | Saito           |       |          |                               |
|                     | AL | 5,789,954       | 08/04/98 | Toeppen et al   |       |          |                               |
|                     | AM | 4,694,244       | 08/15/87 | Whiteside et al |       |          |                               |

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|  |    | DOCUMENT NUMBER | DATE     | COUNTRY | CLASS | SUBCLASS | TRANSLATION |    |
|--|----|-----------------|----------|---------|-------|----------|-------------|----|
|  |    |                 |          |         |       |          | YES         | NO |
|  | AN | JP4105070       | 04/07/92 | Japan   |       |          | Abstract    |    |
|  | AO | JP5196641       | 08/06/93 | Japan   |       |          | Abstract    |    |
|  | AP | JP5264595       | 10/12/93 | Japan   |       |          | Abstract    |    |
|  | AQ | JP8220144       | 06/22/99 | Japan   |       |          | Abstract    |    |
|  | AR | JP9005362       | 01/10/97 | Japan   |       |          | Abstract    |    |
|  | AS | JP10163859      | 06/19/98 | Japan   |       |          | Abstract    |    |
|  | AT | JP11098876      | 04/09/99 | Japan   |       |          | Abstract    |    |
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|  | AV | EP 0 631 143    | 12/28/94 | Europe  |       |          |             |    |
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| AY |  | Roland E. Best, <i>The Software PLL, Phase Locked Loops</i> , 3 <sup>rd</sup> Edition, McGraw-Hill, New York, 1997, pp 229-249 |
| AZ |  | <i>Using FPGAs for Digital Applications</i> , Actel Corporation, April 1996  |
| BA |  | HP E4543A Q Factor and Eye Contours Application Software, Hewlett Packard, 1999  |
| BB |  | Infinium DCA, Agilent Technologies, March 7, 2002  |
| BC |  | Communication waveform measurements, Hewlett Packard, June 26, 1996  |

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\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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## LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

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|---------------------|----|-----------------|------|------|-------|----------|-------------------------------|
|                     | BD |                 |      |      |       |          |                               |
|                     | BE |                 |      |      |       |          |                               |
|                     | BF |                 |      |      |       |          |                               |

## FOREIGN PATENT DOCUMENTS

|  |    | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION |    |
|--|----|-----------------|------|---------|-------|----------|-------------|----|
|  |    |                 |      |         |       |          | YES         | NO |
|  | BG |                 |      |         |       |          | Abstract    |    |
|  | BH |                 |      |         |       |          | Abstract    |    |
|  | BI |                 |      |         |       |          |             |    |

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|  | BJ |  | Advanced Analysis of High-Speed Digital Communication Waveforms, Hewlett Packard, June 27, 1994   |
|  | BK |  | R.E. Anderson and E. M. Foster, Design of an MPEG-2 Transport Demultiplexor Core, IBM, 1999   |
|  | BL |  | Technology Standards, Tektronix Website ( <a href="http://www.tek.com/Masurement/Solutions/tech_standards/index.html?wt=257">www.tek.com/Masurement/Solutions/tech_standards/index.html?wt=257</a> )  |
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|  | BQ |  | Low Jitter Digital PLL - ZL30407, Zalink Semiconductor Website, ( <a href="http://products.zalink.com/product_portlets/new_timer.htm">http://products.zalink.com/product_portlets/new_timer.htm</a> ) |
|  | BR |  | Michael K. Williams, et al., A Discussion of Methods for Measuring Low-Amplitude Jitter, International Test Conference, Paper 28.1, pp 646-652  |
|  | BS |  | Russ Brown, Quantam Corporation, "Eye Diagram Data", SCSI Physical Working Group, February 9, 2000  |
|  | BT |  | Dave Fink, Tektronix "Introduction to Measurement Techniques and Analysis of Emerging Serial Data Standards", November 2002   |
|  | BU |  | "Methodologies for Jitter Specification Technical Report" Rev 10, June 9, 1999  |
|  | BV |  | Andy Baldman, University of New Hampshire "Description of XAUI Physical Layer Measurements Performed At The UNH Interoperability Lab", October 30, 2002   |
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